

Search Notes

Application/Control No.

10/784,324

Examiner

Paul D. Kim

Applicant(s)/Patent under
Reexamination

NUYTKENS ET AL.

Art Unit

3729

SEARCHED

Class	Subclass	Date	Examiner
29	602.1 606 607 829 832	6/22/2006	PK
205	119 122		
216	67		
336	200 212		
	223 232		
427	99.5	✓	

INTERFERENCE SEARCHED

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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Reviewed Parent Application 09/904,014 (US PAT. 6,696,910)	6/22/2006	PK
Text Search EAST/NPL (IEEE)	6/22/2006	PK